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Practitioner's Docket No.: 081468-0306007
Client Reference No.: P-1556.010-US

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of:

Confirmation No:

VAN HAREN et al.

Application No.: TO BE ASSIGNED

Group No.:

Filed: September 22, 2003

Examiner:

For: A MARKER STRUCTURE FOR OPTICAL ALIGNMENT OF A SUBSTRATE,
A SUBSTRATE INCLUDING SUCH A MARKER STRUCTURE, AN
ALIGNMENT METHOD FOR ALIGNING TO SUCH A MARKER
SUBSTRATE, AND A LITHOGRAPHIC PROJECTION APPARATUS

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

SUBMISSION OF PRIORITY DOCUMENT

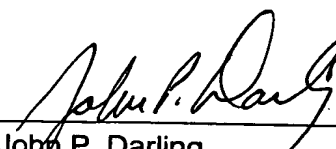
Attached please find the certified copy of the foreign application from which priority is
claimed for this case:

<u>Country</u>	<u>Application Number</u>	<u>Filing Date</u>
EUROPE	03076422.9	05/12/2003

Date: September 22, 2003

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Bescheinigung

Certificate

Attestation

Die angehefteten Unterlagen stimmen mit der ursprünglich eingereichten Fassung der auf dem nächsten Blatt bezeichneten europäischen Patentanmeldung überein.

The attached documents are exact copies of the European patent application described on the following page, as originally filed.

Les documents fixés à cette attestation sont conformes à la version initialement déposée de la demande de brevet européen spécifiée à la page suivante.

Patentanmeldung Nr. Patent application No. Demande de brevet n°

03076422.9

Der Präsident des Europäischen Patentamts:
Im Auftrag

For the President of the European Patent Office

Le Président de l'Office européen des brevets
p.o.

R C van Dijk



Anmeldung Nr:
Application no.: 03076422.9
Demande no:

Anmeldetag:
Date of filing: 12.05.03
Date de dépôt:

Anmelder/Applicant(s)/Demandeur(s):

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PAYS-BAS

Bezeichnung der Erfindung/Title of the invention/Titre de l'invention:
(Falls die Bezeichnung der Erfindung nicht angegeben ist, siehe Beschreibung.
If no title is shown please refer to the description.
Si aucun titre n'est indiqué se référer à la description.)

Lithographic marker structure compliant with microelectronic device processing,
lithographic projection apparatus comprising such a lithographic marker structure
and method for wafer alignment using such a lithographic marker structure

In Anspruch genommene Priorität(en) / Priority(ies) claimed /Priorité(s)
revendiquée(s)
Staat/Tag/Aktenzeichen/State/Date/File no./Pays/Date/Numéro de dépôt:

Internationale Patentklassifikation/International Patent Classification/
Classification internationale des brevets:

G03F/

Am Anmeldetag benannte Vertragstaaten/Contracting states designated at date of
filing/Etats contractants désignées lors du dépôt:

AT BE BG CH CY CZ DE DK EE ES FI FR GB GR HU IE IT LU MC NL
PT RO SE SI SK TR LI